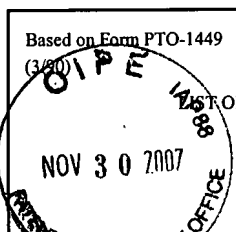


Based on Form PTO-1449 (3/80) 	ATTY. DOCKET NO. 455610-2590.1	SERIAL NO. 10/673,736
	APPLICANT Martin Thomas Miller	
	FILING DATE September 29, 2003	GROUP 2117

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ	Technology Standards, Tektronix Website (www.tek.com/M Measurement/Solutions/tech_standards/index.html?wt=257), July 16, 2003
	AR	Communications Signal Analyzer, Communications Eye-diagram Measurements Software, Tektronix website (http://www.tektronix.com), May 12, 2003
	AS	RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix website(www.tektronix.com/accessories), September 20, 2002
	AT	Design of FIR Filters by Windowing, HST-582J/6.555J/16.456J, Biomedical Signal and Image Processing Spring 2001, (http://web.mit.edu/6.555/www/fir.html), August 5, 2003
	AU	A New Digital PLL at the Technische Universitaet Berlin , The Cooperation Project, (http://www.tdl.com/~gottsch/tuberlin.htm), August 5, 2003
	AV	Low Jitter Digital PLL - ZL 30407, Zarlink Semiconductur, (http://products.zarlink.com/product_portlets/new_timer.htm) , August 5, 2003
		Williams. Michael, "A Discussion of Methods for Measuring Low-Amplitude Jitter", International Test Conference, Paper 28.1, pp. 646-652, 1995 IEEE
		University of New Hampshire, "Fast Ethernet, Clause 25 Physical Medium Dependemt Test Suite Version 2.5, February 13, 2003

EXAMINER

DATE CONSIDERED

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.